PMV31XN

µTrenchMOS™ extremely low level FET

Rev. 01 — 26 February 2003

Product data

1. Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS $^{\text{TM}}$ technology.

Product availability:

PMV31XN in SOT23.

2. Features

- TrenchMOS[™] technology
- Very fast switching
- Low threshold voltage
- Surface mount package.

3. Applications

- Battery powered motor control
- High-speed switch in set top box power supplies.

4. Pinning information

Table 1: Pinning - SOT23, simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1	gate (g)	— ∏3	d
2	source (s)		
3	drain (d)	1 2 Top view MSB003 SOT23	д ВВВО76





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5. Quick reference data

Table 2: Quick reference data

Symbol	Parameter	Conditions	Тур	Max	Unit
V_{DS}	drain-source voltage (DC)	$25 ^{\circ}\text{C} \le T_j \le 150 ^{\circ}\text{C}$	-	20	V
I_D	drain current (DC)	T_{sp} = 25 °C; V_{GS} = 4.5 V	-	5.9	Α
P _{tot}	total power dissipation	$T_{sp} = 25 ^{\circ}C$	-	2	W
Tj	junction temperature		-	150	°C
R_{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 1.5 \text{ A}; T_j = 25 ^{\circ}\text{C}$	31	37	$m\Omega$
		V_{GS} = 2.5 V; I_D = 1 A; T_j = 25 °C	44	53	$m\Omega$

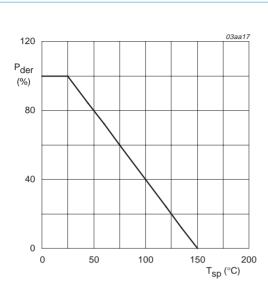
6. Limiting values

Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

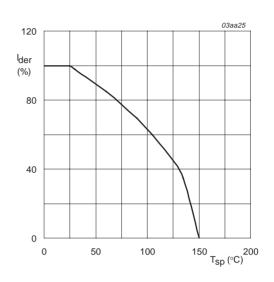
Symbol	Parameter	Conditions	Min	Max	Unit	
V_{DS}	drain-source voltage (DC)	25 °C ≤ T _j ≤ 150 °C	-	20	V	
V_{DSR}	drain-source voltage (DC)	$25~^{\circ}\text{C} \le \text{T}_{\text{j}} \le 150~^{\circ}\text{C}; \text{R}_{\text{GS}} = 20~\text{k}\Omega$	-	20	V	
V_{GS}	gate-source voltage (DC)		-	±12	V	
I _D	drain current (DC)	T_{sp} = 25 °C; V_{GS} = 4.5 V; Figure 2 and 3	-	5.9	Α	
		$T_{sp} = 100 ^{\circ}\text{C}; V_{GS} = 4.5 \text{V}; \text{Figure 2}$	-	3.75	Α	
I _{DM}	peak drain current	T_{sp} = 25 °C; pulsed; $t_p \le 10 \mu s$; Figure 3	-	23.7	Α	
P _{tot}	total power dissipation	T _{sp} = 25 °C; Figure 1	-	2	W	
T _{stg}	storage temperature		– 55	+150	°C	
T _j	junction temperature		– 55	+150	°C	
Source-drain diode						
Is	source (diode forward) current (DC)	T _{sp} = 25 °C	-	1.7	Α	

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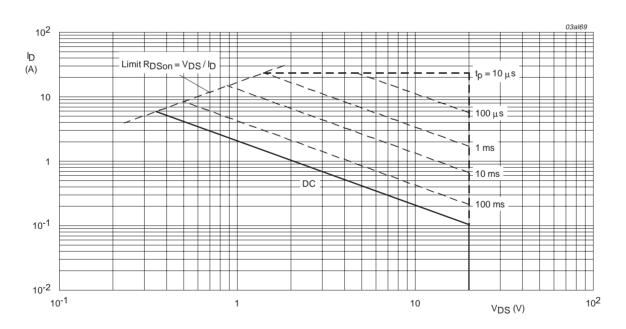
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature.



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature.



 $T_{sp} = 25 \,^{\circ}C$; I_{DM} is single pulse.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

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7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-sp)}	thermal resistance from junction to solder point	Figure 4	-	-	60	K/W

7.1 Transient thermal impedance

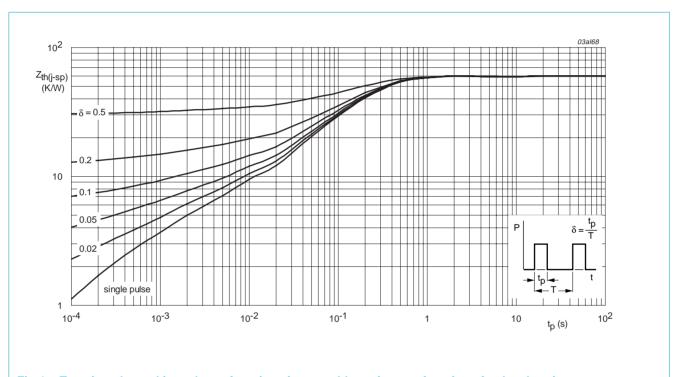


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration.

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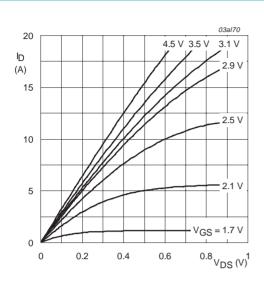
8. Characteristics

Table 5: Characteristics

 $T_i = 25 \,^{\circ}C$ unless otherwise specified.

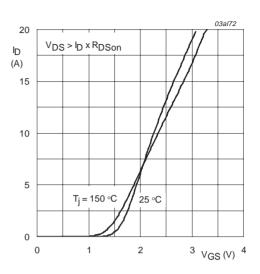
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 250 \mu\text{A}; V_{GS} = 0 \text{V}$				
		T _j = 25 °C	20	-	-	V
		T _j = −55 °C	18	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; Figure 9				
		T _j = 25 °C	0.5	-	1.5	V
		T _j = 150 °C	0.35	-	-	V
		T _j = −55 °C	-	-	1.8	V
I _{DSS}	drain-source leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	-	1	μΑ
		T _j = 150 °C	-	-	100	μΑ
I_{GSS}	gate-source leakage current	$V_{GS} = \pm 12 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nΑ
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 1.5 \text{ A}; Figure 7 and 8$	-	31	37	$m\Omega$
		$V_{GS} = 2.5 \text{ V}; I_D = 1 \text{ A}; Figure 7 and 8$	-	44	53	$m\Omega$
Dynamic	characteristics					
Q _{g(tot)}	total gate charge	$V_{DD} = 10 \text{ V}; V_{GS} = 4.5 \text{ V}; I_D = 6 \text{ A}; Figure 13$	-	5.8	-	nC
Q_{gs}	gate-source charge		-	1.4	-	nC
Q_{gd}	gate-drain (Miller) charge		-	1.7	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 20 \text{ V}; f = 1 \text{ MHz}; Figure 11$	-	410	-	pF
C _{oss}	output capacitance		-	115	-	pF
C _{rss}	reverse transfer capacitance		-	80	-	pF
t _{d(on)}	turn-on delay time	V_{DD} = 10 V; R_D = 10 Ω ; V_{GS} = 4.5 V; R_G = 6 Ω	-	10	-	ns
t _r	rise time	_		15	-	ns
t _{d(off)}	turn-off delay time			25	-	ns
t _f	fall time		-	12	-	ns
Source-	drain diode					
V_{SD}	source-drain (diode forward) voltage	I _S = 1.5 A; V _{GS} = 0 V; Figure 12	-	0.75	1.2	V

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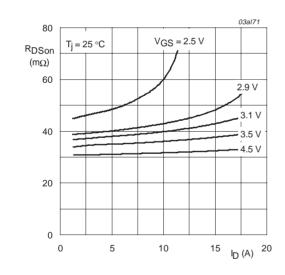
T_i = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



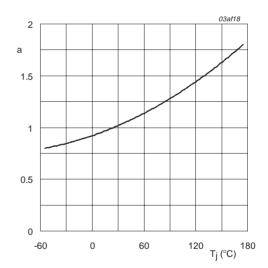
 T_j = 25 °C and 150 °C; V_{DS} > I_D x R_{DSon}

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.



 $T_j = 25 \, ^{\circ}C$

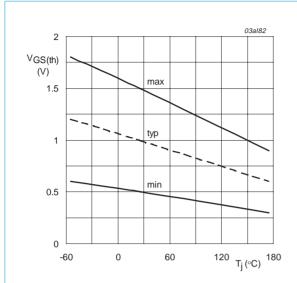
Fig 7. Drain-source on-state resistance as a function of drain current; typical values.



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

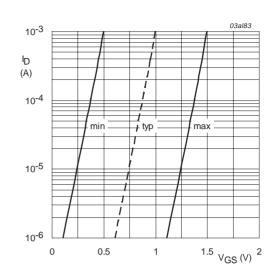
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature.

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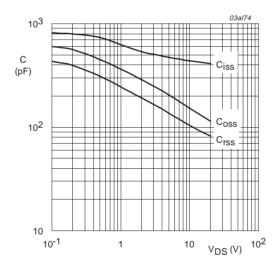
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature.



 $T_i = 25 \,^{\circ}C; \, V_{DS} = 5 \,^{\circ}V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage.



 $V_{GS} = 0 V$; f = 1 MHz

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

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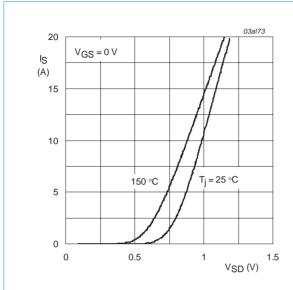
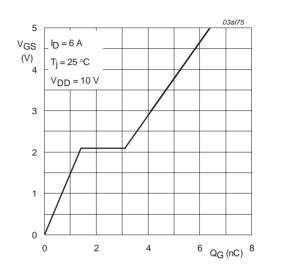


Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.

 T_i = 25 °C and 150 °C; V_{GS} = 0 V



 $I_D = 6 A; V_{DD} = 10 V$

Fig 13. Gate-source voltage as a function of gate charge; typical values.

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9. Package outline

Plastic surface mounted package; 3 leads

SOT23

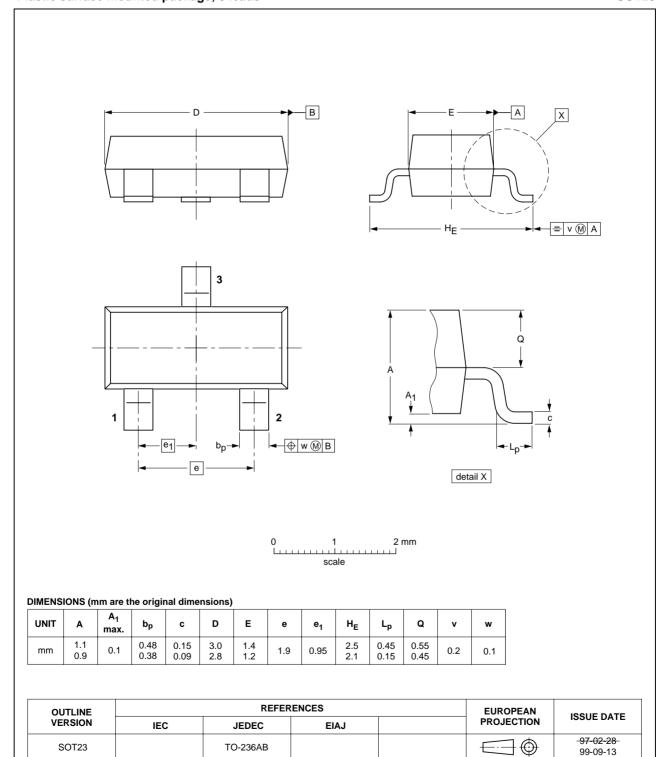


Fig 14. SOT23.



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10. Revision history

Table 6: Revision history

Rev	Date	CPCN	Description
01	20030226	-	Product data (9397 750 11066)

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11. Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2][3]}	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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- [1] Please consult the most recently issued data sheet before initiating or completing a design.
- [2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- [3] For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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